

**Notice of Allowability**

Application No.	Applicant(s)	
09/671,261	TAKEUCHI, YUTAKA	
Examiner	Art Unit	
Jeanne A. Di Grazio	2871	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTO-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1.  This communication is responsive to Amendment of 18 May 2004.
2.  The allowed claim(s) is/are 1 and 3-6.
3.  The drawings filed on 28 September 2000 are accepted by the Examiner.
4.  Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
  - a)  All
  - b)  Some\*
  - c)  None of the:
  1.  Certified copies of the priority documents have been received.
  2.  Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
  3.  Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

\* Certified copies not received: \_\_\_\_\_.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.  
**THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.**

5.  A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
6.  CORRECTED DRAWINGS ( as "replacement sheets") must be submitted.
  - (a)  including changes required by the Notice of Draftsperson's Patent Drawing Review ( PTO-948) attached  
1)  hereto or 2)  to Paper No./Mail Date \_\_\_\_\_.
  - (b)  including changes required by the attached Examiner's Amendment / Comment or in the Office action of  
Paper No./Mail Date \_\_\_\_\_.
7.  DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

**Attachment(s)**

1.  Notice of References Cited (PTO-892)
2.  Notice of Draftsperson's Patent Drawing Review (PTO-948)
3.  Information Disclosure Statements (PTO-1449 or PTO/SB/08),  
Paper No./Mail Date 6, 8, 9, 12
4.  Examiner's Comment Regarding Requirement for Deposit  
of Biological Material
5.  Notice of Informal Patent Application (PTO-152)
6.  Interview Summary (PTO-413),  
Paper No./Mail Date \_\_\_\_\_.
7.  Examiner's Amendment/Comment
8.  Examiner's Statement of Reasons for Allowance
9.  Other \_\_\_\_\_.

**DETAILED ACTION**

*Claims*

Claims 1 and 3-6 are pending. Claim 2 has been cancelled per Applicant's Amendment of May 18, 2004.

*Allowable Subject Matter*

Claims 1 and 3-6 are allowed.

The following is an examiner's statement of reasons for allowance:

As to claim 1, relevant art of record did not disclose, alone or in combination, a liquid crystal device comprising an electrode width of an electrode strip on a step portion narrower than an electrode width of an electrode strip on a protective layer in a formation region and a part of an electrode width of an electrode strip within an unformed region of the protective layer equal to an electrode width of an electrode strip on the protective layer within the formation region and enabling measurement of electrode gap and further in combination with Applicant's other recited limitations.

The above structure results in a novel liquid crystal display device in which electrode gap can be measured without short-circuiting of neighboring electrodes.

The closest combination is Applicant's Admitted Prior Art ("APA") in view of United States Patent 5,986,739 (to Kobayashi). However, neither reference teaches and discloses testing of electrodes (or measurement of electrode gap) at a wide portion of the electrodes and in further combination with the other elements of claim 1.

As to claim 4, relevant art of record did not disclose, alone or in combination, a liquid crystal device comprising an electrode width of an electrode strip in a step portion narrower than an electrode width of an electrode strip on a protective layer in a formation region by approximately 4 $\mu$ m and a part of an electrode width of an electrode strip within an unformed region of the protective layer equal to an electrode width of an electrode strip on the protective layer within the formation region and enabling measurement of electrode gap and further in combination with Applicant's other recited limitations.

The above structure results in a novel liquid crystal display device in which electrode gap can be measured without short-circuiting of neighboring electrodes.

The closest combination is Applicant's Admitted Prior Art ("APA") in view of United States Patent 5,986,739 (to Kobayashi). However, neither reference teaches and discloses testing of electrodes (or measurement of electrode gap) at a wide portion of the electrodes and in further combination with the other elements of claim 4.

As to claims 3, 5 and 6, they are dependent either directly or indirectly upon claims with allowable subject matter above.

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Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

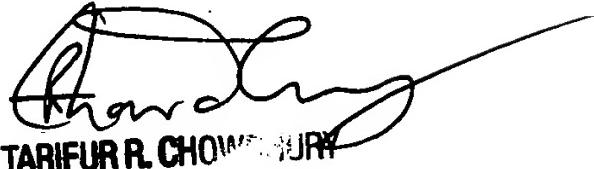
Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jeanne A. Di Grazio whose telephone number is (571)272-2289. The examiner can normally be reached on M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robert Kim, can be reached on (571)272-2293. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Jeanne Andrea Di Grazio  
Patent Examiner  
Art Unit 2871

JDG



TARIFUR R. CHOWDHURY  
PRIMARY